

TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT
(Under 37 CFR 1.97(b) or 1.97(c))

Docket No.
SEC.936

In Re Application Of: **Jai-Young WOO et al.**

1005
#8-10-1703

Serial No. 10/071,099	Filing Date 11 February 2002	Examiner Thong Q. NGUYEN	Group Art Unit 2872
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TitleP MICROSCOPE FOR INSPECTING SEMICONDUCTOR WAFER

OCT 10 2003

PATENT & TRADEMARK OFFICE
U.S. DEPARTMENT OF COMMERCE

Address to:
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

37 CFR 1.97(b)

1. The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application other than a continued prosecution application under 37 CFR 1.53(d); within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; before the mailing of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 CFR 1.114.

37 CFR 1.97(c)

2. The Information Disclosure Statement submitted herewith is being filed after the period specified in 37 CFR 1.97(b), provided that the Information Disclosure Statement is filed before the mailing date of a Final Action under 37 CFR 1.113, a Notice of Allowance under 37 CFR 1.311, or an Action that otherwise closes prosecution in the application, and is accompanied by one of:
 - the statement specified in 37 CFR 1.97(e);

OR

 - the fee set forth in 37 CFR 1.17(p).
3. Also enclosed is a copy of an Office Action dated 29 July 2003 issued by the German Patent Office, in connection with Official File No. 102 11 922.8-42 wherein the enclosed references were cited.

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**STATEMENT UNDER 37 CFR 1.97(e) ACCOMPANYING
INFORMATION DISCLOSURE STATEMENT**

Docket No.
SEC.936

In Re Application Of: Jai-Young WOO et al.

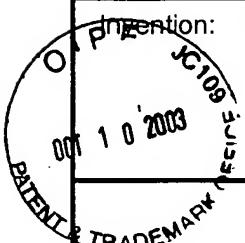
Serial No.
10/071,099

Filing Date
11 February 2002

Examiner
Thong Q. Nguyen

Group Art Unit
2872

Invention: MICROSCOPE FOR INSPECTING SEMICONDUCTOR WAFER



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TO THE COMMISSIONER FOR PATENTS:

This is a statement under the provisions of 37 CFR 1.97(e) in the above-identified application.

Check applicable statement herebelow:

Statement Under 37 CFR 1.97(e)(1)

Each item of information contained in the accompanying Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Information Disclosure Statement.

Statement Under 37 CFR 1.97(e)(2)

No item of information contained in the accompanying Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the undersigned person, after making reasonable inquiry, no item of information contained in the accompanying Information Disclosure Statement was known to any individual designated in 37 CFR 1.56(c) more than three months prior to the filing of the Information Disclosure Statement.



Signature

Dated: 10 October 2003

KENNETH D. SPRINGER

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EXAMINEE

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.